N-Ch MOSFET

General Description

The WST4040 is the highest performance trench N-ch MOSFETs with extreme high cell density, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications.

The WST4040 meet the RoHS and Green Product requirement,100% EAS guaranteed with full function reliability approved.

Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- 100% EAS Guaranteed
- Green Device Available

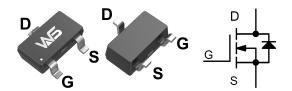
Product Summery

BVDSS	RDSON	ID
40V	35mΩ	5.8A

Applications

- High Frequency Point-of-Load Synchronous Buck Converter for MB/NB/UMPC/VGA
- Networking DC-DC Power System
- Load Switch

SOT-23-3L Pin Configuration



Absolute Maximum Ratings

Symbol	Parameter	Rating	Units	
V_{DS}	Drain-Source Voltage	40	V	
V_{GS}	Gate-Source Voltage	±20	V	
I _D @T _C =25℃	Continuous Drain Current, V _{GS} @ 4.5V ¹	5.8	Α	
I _D @T _C =70℃	Continuous Drain Current, V _{GS} @ 4.5V ¹	2.5	А	
I _{DM}	Pulsed Drain Current ²	16	Α	
P _D @T _A =25°C	Total Power Dissipation ³	1.0	W	
T _{STG}	Storage Temperature Range	-55 to 150	$^{\circ}$	
T_J	Operating Junction Temperature Range	-55 to 150	${\mathbb C}$	

Thermal Data

Symbol	Parameter	Тур.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction-ambient ¹		125	°C/W
$R_{ heta JC}$	Thermal Resistance Junction-Case ¹		75	°C/W

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Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	40			V
$\triangle BV_{DSS}/\triangle T_{J}$	BVDSS Temperature Coefficient	Reference to 25℃ , I _D =1mA		0.0		V/°C
D	Static Drain-Source On-Resistance ²	V _{GS} =10V , I _D =3A		35	50	0
R _{DS(ON)}	Static Dialii-Source On-Resistance	V _{GS} =4.5V , I _D =2A		50	60	mΩ
V _{GS(th)}	Gate Threshold Voltage)/ -)/ -250··A	0.6	1.0	1.6	V
$\triangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	$V_{GS}=V_{DS}$, $I_D=250uA$		4.5		mV/℃
	Dunin Course Lookens Current	V_{DS} =32V , V_{GS} =0V , T_{J} =25 $^{\circ}$ C		-	1	
I _{DSS}	Drain-Source Leakage Current	V_{DS} =32V , V_{GS} =0V , T_{J} =55 $^{\circ}$ C		-	5	uA
I _{GSS}	Gate-Source Leakage Current	V_{GS} = $\pm 20V$, V_{DS} = $0V$		-	±100	nA
gfs	orward Transconductance	V _{DS} =5V , I _D =3A		18		S
R_g	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		1.7		Ω
Q_g	Total Gate Charge (4.5V)	V _{DS} =20V , V _{GS} =4.5V , I _D =2A		6.5	12.5	
Q_{gs}	Gate-Source Charge			0.8	3.5	nC
Q_{gd}	Gate-Drain Charge			1.65	4.2	
T _{d(on)}	Turn-On Delay Time			1.5	4.8	
Tr	Rise Time	V_{DD} =20V , V_{GS} =10V , R_G =3.3 Ω		42	14	
T _{d(off)}	Turn-Off Delay Time			18	44	ns
T _f	Fall Time			5.9	8	
C _{iss}	Input Capacitance	V _{DS} =15V , V _{GS} =0V , f=1MHz		396	497	
Coss	Output Capacitance			47	112	pF
C _{rss}	Reverse Transfer Capacitance			35	91	

Guaranteed Avalanche Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
EAS	Single Pulse Avalanche Energy ⁵	V _{DD} =25V , L=0.1mH , I _{AS} =2A	9			mJ

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current ^{1,6}	V =V =0V Force Current			1	Α
I _{SM}	Pulsed Source Current ^{2,6}	$V_G=V_D=0V$, Force Current			16	Α
V_{SD}	Diode Forward Voltage ²	V _{GS} =0V , I _S =1A , T _J =25℃			1.2	V
t _{rr}	Reverse Recovery Time	IF=2A , dI/dt=100A/ μ s , T $_{J}$ =25 $^{\circ}$ C		18		nS
Qrr	Reverse Recovery Charge	IF=2A , dI/dt=100A/ μ s , T $_{J}$ =25 $^{\circ}$ C		70		nC

Note:

- 1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper, t<10 sec.
- 2.The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%
- 3.The EAS data shows Max. rating . The test condition is V_{DD} =25V, V_{GS} =10V,L=0.1mH,I_{AS}=2A
- 4.The power dissipation is limited by 150℃ junction temperature
- 5. The Min. value is 100% EAS tested guarantee.
- 6. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.



Typical Characteristics

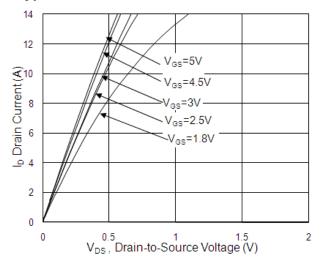


Fig.1 Typical Output Characteristics

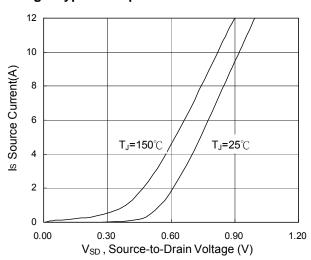


Fig.3 Forward Characteristics Of Reverse

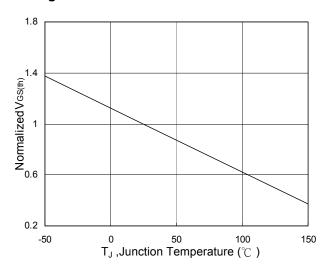


Fig.5 Normalized V_{GS(th)} vs. T_J

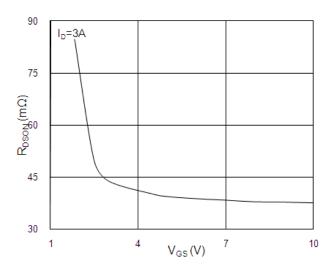


Fig.2 On-Resistance vs. Gate-Source

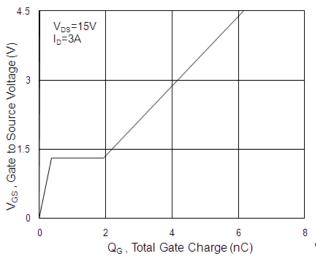


Fig.4 Gate-Charge Characteristics

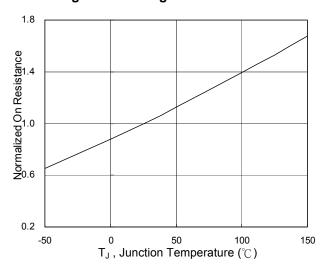
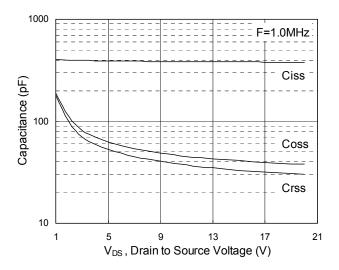


Fig.6 Normalized R_{DSON} vs. T_J





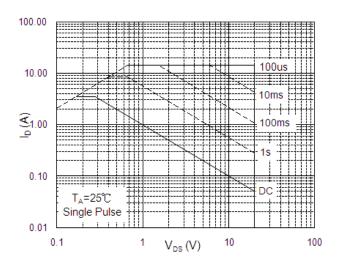


Fig.7 Capacitance

Fig.8 Safe Operating Area

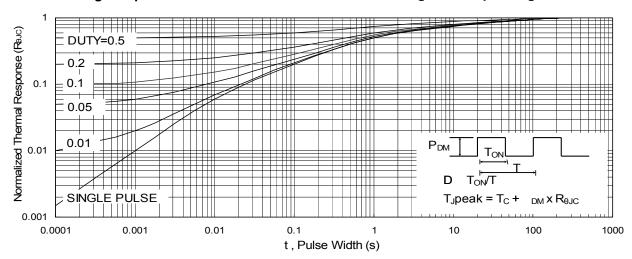
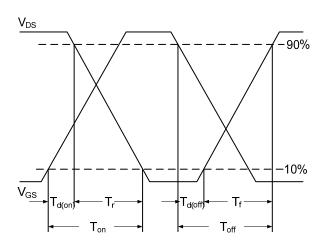
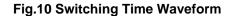


Fig.9 Normalized Maximum Transient Thermal Impedance





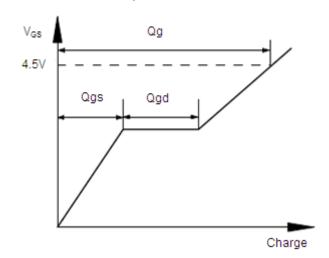


Fig.11 Gate Charge Waveform



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